

RELIABILITY REPORT
FOR
MAX5237EUB+
PLASTIC ENCAPSULATED DEVICES

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MAXIM INTEGRATED

160 RIO ROBLES
SAN JOSE, CA 95134

Approved by
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Conclusion

The MAX5237EUB+ successfully meets the quality and reliability standards required of all Maxim Integrated products. In addition, Maxim Integrated's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim Integrated's quality and reliability standards.

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I. Device Description

A. General

The MAX5236/MAX5237 precision, dual, voltage-output, 10-bit digital-to-analog converters (DACs) consume only 360 μ A from a single 5V (MAX5237) or 325 μ A from a single 3V (MAX5236) supply. These devices feature output buffers that swing rail-to-rail. The internal gain amplifiers (1.6384V/V) maximize the dynamic range of the DAC output. The MAX5236/MAX5237 feature 13.5MHz a 3-wire serial interface compatible with SPI and QSPI and MICROWIRE. Each DAC input is organized as an input register followed by a DAC register. A 16-bit shift register loads data into the input registers. Input registers update the DAC registers independently or simultaneously. In addition, programmable control bits allow power-down with 1k or 200k internal loads. The MAX5236/MAX5237 are fully specified over the extended industrial temperature range (-40°C to +85°C) and are available in space-saving 10-pin μ MAX® packages.

II. Manufacturing Information

A. Description/Function:	Single-Supply 3V/5V, Voltage-Output, Dual, Precision 10-Bit DACs
B. Process:	C6Y
C. Number of Device Transistors:	4184
D. Fabrication Location:	Japan
E. Assembly Location:	Thailand, Malaysia
F. Date of Initial Production:	January 26, 2002

III. Packaging Information

A. Package Type:	10-pin uMAX
B. Lead Frame:	NiPd
C. Lead Finish:	100% matte Tin
D. Die Attach:	Non-conductive
E. Bondwire:	Au (1 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-0401-0555
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Ja:	180°C/W
K. Single Layer Theta Jc:	41.9°C/W
L. Multi Layer Theta Ja:	113.1°C/W
M. Multi Layer Theta Jc:	41.9°C/W

IV. Die Information

A. Dimensions:	75X88 mils
B. Passivation:	Si ₃ N ₄ /SiO ₂ (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Al with Ti/TiN Barrier
D. Backside Metallization:	None
E. Minimum Metal Width:	0.6 microns (as drawn)
F. Minimum Metal Spacing:	0.6 microns (as drawn)
G. Bondpad Dimensions:	
H. Isolation Dielectric:	SiO ₂
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

- A. Quality Assurance Contacts: Don Lipps (Manager, Reliability Engineering)
Bryan Preeshl (Vice President of QA)
- B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% for all Visual Defects.
- C. Observed Outgoing Defect Rate: < 50 ppm
- D. Sampling Plan: Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135C biased (static) life test are shown in Table 1. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{192 \times 4340 \times 45 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$$\lambda = 24.4 \times 10^{-9}$$

$$\lambda = 24.4 \text{ F.I.T. (60\% confidence level @ 25}^\circ\text{C)}$$

The following failure rate represents data collected from Maxim Integrated's reliability monitor program. Maxim Integrated performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at <http://www.maximintegrated.com/qa/reliability/monitor>. Cumulative monitor data for the C6Y Process results in a FIT Rate of 0.17 @ 25C and 2.89 @ 55C (0.8 eV, 60% UCL).

B. E.S.D. and Latch-Up Testing (lot S6P0BQ001G, 0825)

The DA91 die type has been found to have all pins able to withstand a HBM transient pulse of +/-1500V per Mil-Std 883 Method 3015.7. Latch-Up testing has shown that this device withstands a current of +/-250mA and overvoltage per JEDEC JESD78.

Table 1
Reliability Evaluation Test Results

MAX5237EUB+

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES	COMMENTS
Static Life Test (Note 1)	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	45	0	I6P1AQ001D, D/C 0149

Note 1: Life Test Data may represent plastic DIP qualification lots.